

Notice of References Cited			Application/Control No.	Applicant(s)/Patent Under Reexamination HAMANO ET AL.	
			Examiner FRANK D. DUCHENEAUX	Art Unit 1794	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2004/0173940	09-2004	Yuhara et al.	264/259
*	B US-2003/0183495	10-2003	Kashino, Masayuki	200/341
*	C US-2004/0251634	12-2004	Shimazu et al.	277/434
*	D US-2001/0040001	11-2001	Toyooka, Naoto	156/233
*	E US-5,824,252	10-1998	Miyajima, Fumio	264/272.17
*	F US-2005/0116386	06-2005	Hamano et al.	264/279
*	G US-4,917,927	04-1990	Sakaitani et al.	428/42.1
*	H US-5,922,369	07-1999	Yanagihara et al.	425/572
*	I US-2001/0038493	11-2001	Watanabe et al.	359/609
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	WO 03013823 A1	02-2003	World Intellect	KURAMITSU M et al.	B29C 45/14
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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X	

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